## K ondo resonances and anom alous gate dependence of electronic conduction in single-m olecule transistors

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W e report K ondo resonances in the conduction of single-m olecule transistors based on transition m etal coordination com plexes. W e nd K ondo tem peratures in excess of 50 K, com parable to those in purely m etallic system s. The observed gate dependence of the K ondo tem perature is inconsistent with observations in sem iconductor quantum dots and a simple single-dot-levelm odel. W e discuss possible explanations of this e ect, in light of electronic structure calculations.

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In the Kondo Ham iltonian [1], one of the most wellstudied m any-body problem s in physics, an unpaired spin localized in a singly occupied electronic level is coupled via tunneling to an electronic bath. On-site C oulom b repulsion forbids real double occupancy of the level, but virtual processes favor antiferrom agnetic exchange between the local spin and the electronic bath. As T is reduced below a characteristic Kondo tem perature,  $T_{\text{K}}$  , these exchange processes \screen" the local moment. The K ondo problem has undergone a resurgence, with atom ic-scale studies of K ondo physics by scanning tunneling m icroscopy (STM) [2, 3] and the realization of tunable K ondo systems in sem iconductor quantum dots[4, 5, 6, 7]. W ith the recent developm ent of singlemolecule transistors (SMTs) based on individual small m olecules [8], K ondo system s now include organom etallic com pounds [9, 10] and fullerenes with norm al [11] and ferrom agnetic [12] leads.

In this Letter, we report K ondo physics in SM T s incorporating transition m etal com plexes designed to contain unpaired electrons. As a function of gate voltage,  $V_{G}$ , we observe transitions from Coulomb blockade conduction to K ondo conduction, m an ifested as a strong peak in the di erential conductance, G  $0 \downarrow = 0 V_{SD}$ , at zero bias,  $V_{SD} = 0$  in one charge state. At xed V<sub>G</sub>, the tem perature dependence of the conductance peaks' am plitudes and widths agree well with the expected form s for spin-1/2 K ondo resonances. O bserved SM T K ondo tem peratures are > 50 K, com parable to those in purely m etallic K ondo system s. We nd that  $T_k(V_G)$  is strongly inconsistent with the simplem odel of K ondo physics as seen in sem iconductor devices [6, 7]. W e discuss explanations for this anom alous gate dependence in light of spin-resolved electronic structure calculations of the com plexes.

Figure 1a shows the simple single-level picture often used to describe K ondo physics in single-electron transistors (SET s). The intrinsic width of the single particle level is  $_{S} + _{D}$ , determ ined by overlap of the singleparticle state with the conduction electron states of the source and drain. The charging energy E $_{\rm c}$  is the C oulom b cost of adding an extra electron to the molecule. The energy di erence between the singly occupied level and the source/drain chemicalpotential is , which is zero at charge degeneracy and varies linearly with V\_G .

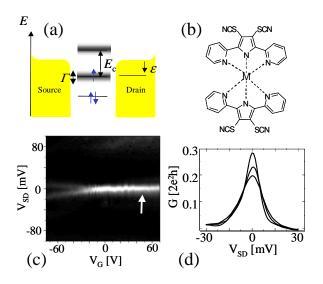


FIG.1: (a) Energy level diagram of a typical SET in the K ondo regime. (b) Structural formula of transition m etal complex before self-assembly. (c) M ap of G ( $V_{SD}$ ; $V_G$ ) showing transition to K ondo resonance at 5 K.B rightness scales from G = 0 (black) to 0:3  $2e^2=h$ . (d) G vs.  $V_{SD}$  at  $V_G$  = 50 V (as indicated with arrow in (c)) at (top to bottom ) 5 K, 16 K, and 30 K.

Figure 1b shows the structure of the neutral transition m etal com plexes m easured in this study, as synthesized. Twoplanar, conjugated ligands provide an octahedral coordination (com pressed along the interligand (z) axis) of a transition m etal ion, M. We have exam ined com plexes with M = Co, Cu, and Zn, as well as individual ligands

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and alkane chains. The K ondo devices in this Letter contain C o (II) and C u (II). The as-synthesized m olecules are characterized by EPR, SQ U ID, x-ray di raction, cyclic voltam m etry (CV), IR, and R am an spectroscopy. The C o (II) com plex is high spin (3/2), with CV in solution con rm ing easily accessible C o (II) C o (III) redox transitions. The C u (II) com plex is spin 1/2, with CV supporting easily accessible C u (II) C u (II) redox transitions. These com plexes self-assem ble on A u in tetrahydrofuran (T H F) through loss of the -C N m oleties and form ation of A u-S covalent bonds [13, 14, 15]. In principle, the ligands and rem aining -SC N groups can also change their charge state.

D evices are fabricated using Au source and drain electrodes on degenerately doped p+ silicon substrates which are used as the gate, with 200 nm of gate oxide. Source/drain electrodes are created by the controlled electrom igration [16] from lithographically de ned T i/A u (1 nm /15 nm thick) constrictions that are exposed for 1 m inute to oxygen plasm a after lifto , followed by selfassem bly ofm olecules in solution (2 mM in THF) for 48 hours. A fter rinsing and drying with dry nitrogen, substrates are placed in a variable tem perature probe station for electrom igration and m easurem ent, with fabrication statistics com parable to past results[11, 14].

DC m easurements of  $I_D$   $V_{\rm SD}$  are performed with the source electrode grounded, at various  $V_G$ . Dierential conductance is computed by numerical dierentiation, with spot checks by lock-in amplier techniques. Device stability limits  $j\!V_{\rm SD}$  j 100 mV, while gate oxide limits  $j\!V_G$  j 100 V.W e consider only devices with significant gate response such that a charge transition is detected in m apsof  $G(V_{\rm SD};V_G)$ , to distinguish m olecule-based e ects from artifacts (e.g. metal nanoparticles).

Figure 1c shows a conductance map for a typical device exhibiting a K ondo resonance. We have su cient gate coupling to observe only a single charge degeneracy point for each device. From the slopes of the boundaries of the blockaded regime, one can estimate the constant of proportionality between changes in  $eV_G$  and as expected from the model of Fig. 1a. For the device shown,

 $(C_G = C_{tot})e V_G$  10 <sup>4</sup> e  $V_G$ . The average value of this coe cient is 10 <sup>3</sup>. The width of the charge degeneracy resonance on the blockaded side of the degeneracy point sets an upper limit on for the level participating in the redox state change. The T ! 0 limit of that width is proportional to , while the degeneracy resonance is therm ally broadened at nite tem perature. Typical values inferred from 5 K data in these devices are 3-30 m eV. W e note that the edges of C oulom b blockade diam onds, while usually distinct in the non-K ondo charge state, are often m uch weaker or apparently absent in the K ondo charge state, as also mentioned in R ef. [12].

Fig. 1d shows G ( $V_{SD}$ ;  $V_G = 50$  V) at three temperatures. The resonant peak decreases in m agnitude while increasing in width as T is increased. Figs. 2a,b show the peak height and width, respectively, as a function of temperature. The solid line in (a) is a t to the

sem iem pirical expression [4] for the spin-1/2 K ondo resonance in conduction, G (T) = G<sub>c</sub> (1 +  $2^{1=s} \frac{1}{T_{K}^{2}}$ )<sup>s</sup>, with s = 0.22. A fler the subtraction of a sm ooth background conductance, the adjustable parameters are the overall conductance scale, G<sub>c</sub>, and T<sub>K</sub>. Sim ilarly, the solid line in (b) is a t to the expected form [3] for the full-width at half-maximum, FW HM =  $\frac{2}{e}^{1}$  ( $k_{B}T$ )<sup>2</sup> + 2 ( $k_{B}T_{K}$ )<sup>2</sup>, where the only adjustable parameter is T<sub>K</sub>. The numerical coe cients are accurate to within a factor of order unity; other observations[7, 10] nd better quantitative consistency with T<sub>K</sub> as inferred from G (V<sub>SD</sub> = 0;T) if the FW HM is assumed to be (2 $k_{B}T_{K}$ )=e. We adopt this latter assumption, and nd good quantitative consistency between T<sub>K</sub> values inferred from resonance height and width.

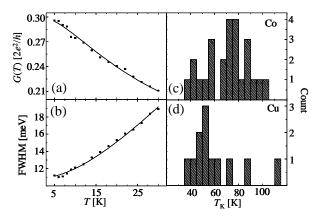


FIG.2: (a) Temperature dependence of K ondo resonant peak height for the device of F ig.1c at  $V_{\rm G}~=~50~V$ . Solid line is the expected sem iempirical functional form for spin-1/2 K ondo, with  $T_{\rm K}~=~69~K$ . (b) Temperature dependence of K ondo peak FW HM for the same device and  $V_{\rm G}$ , with t to expected functional form for spin-1/2 K ondo. Setting FW HM in the low-T limit to  $2k_{\rm B}~T_{\rm K}$  =e gives  $T_{\rm K}~=~65~K$ . (c,d) H istograms of  $T_{\rm K}$  as inferred from peak widths for Co and Cu complex devices, respectively.

F igures 2c,d are histogram s of K ondo tem peratures inferred from resonance widths for 26 C o-containing K ondo devices (out of 921 electrode pairs exam ined at low tem – peratures), and 12 C u-containing K ondo devices (out of 397 electrode pairs exam ined at low tem peratures). O nly devices exhibiting zero-bias resonances and clear charge degeneracy points are considered here. The observed w eak dependence of  $T_K$  on  $V_G$  (see F ig. 3 and later discussion) m eans that these distributions are relatively insensitive to the choice of  $V_G$  at which  $T_K$  is inferred. N o K ondo resonances were observed in 370 control devices using alkanethiol chains, bare m etal electrodes, and electrodes exposed to solvents and poor vacuum.

K ondo physics in these complexes is clearly strong, with  $T_K$  values similar to those reported in STM measurements of C o atom s on Au (111) [2]. The K ondo tem – perature is expected to be [7, 17]:

$$k_{\rm B} T_{\rm K} = \frac{P - E_{\rm C}}{2} e^{(-E_{\rm C}) = E_{\rm C}}$$
(1)

outside the mixed valence ( = < 1) regime. For small molecules,  $E_c$  is likely to be hundreds of meV, while is empirically tens of meV. The prefactor in (1) then implies  $T_K$  can be as large as hundreds of K elvin.

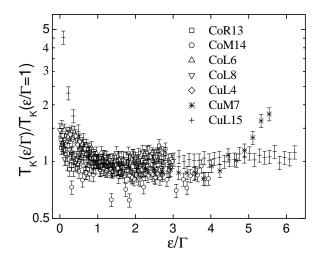


FIG.3: Log  $T_{\rm K}$  (norm alized) inferred from FW HM of 5 K K ondo peak in G ( $V_{\rm SD}$ ), as a function of  $V_{\rm G}$  norm alized by the width of the C oulom b blockade charge degeneracy point (= = in the sim plem odel of Fig.1a) for several devices. In the m odel of Fig.1a, a parabolic dependence of log  $T_{\rm K}$  on  $V_{\rm G}$  is expected. Values of inferred for these devices are, top down, 22.6, 11.5, 18, 3.3, 12.6, 14.2, and 26.8 m eV.

Assuming a model as in Fig. 1a, = 0 at the charge degeneracy point. Normalizing the di erence in  $V_{\rm G}$  away from charge degeneracy by the width in  $V_G$  of the charge degeneracy resonance in the Coulomb blockade regime gives a lower lim it on = . Figure 3 shows (norm alized) TK as inferred from low -T resonance FW HM  $2k_{\rm B} T_{\rm K} = e$ as a function of inferred = for several devices. Eq. (1)predicts a quadratic dependence of  $\log T_{K}$  on  $% T_{K}$  , with a m in im um in  $T_K$  at =  $E_c=2$ . The measured dependence of inferred  $T_K$  ( $V_G$  ) is much less steep; indeed, for Sam ple CuM 7,  $T_K$  actually increases as  $V_G$  is shifted away from the nearest charge degeneracy. Thus, the simple model of Fig. 1a, which works well for sem iconductor quantum dot experim ents[6, 7], is inconsistent with this data. We note that the  $T_K$  (V<sub>G</sub>) dependence reported in R ef. [9] for = > 1 is also surprisingly weak.

W e consider explanations for this deviation from sin – ple expectations. W e dism iss as unlikely that the zerobias peak m ay not be a true K ondo resonance, given (a) quantitative consistency of the functional forms for the resonance G ( $V_{SD}$ ;T) with K ondo expectations; (b) the appearance of the zero-bias resonance coincident with passing through charge degeneracy points; (c) the lack of such resonances in control devices; (d) the sim ilarity to other K ondo data reported in SM T s[9, 10].

The natural explanation for the anom alous gate dependence is that the normalized  $V_G$  used as = in Fig.3 is not the true = relevant to the K ondo H am iltonian that gives Eq. (1). In sem iconductor quantum dots[6] inferring = by normalizing V is quantitatively consistent

Orbital degeneracy for the unpaired spin is one possibility [18]. When an N-fold degeneracy exists,  $T_{K}$ as de ned by Eq. (1) is enhanced, such that the denom inator of the exponent becomes N  $E_c$ . Thus the norm alization of the abcissa in Fig. 3 would e ectively be too large by a factor of N , qualitatively explaining the apparently weak dependence of  $T_{K}\ (\!V_{G}\!$  ) if N5. However, EPR spectra of both the Co and Cu-based complexes in solution phase show no indication of such a large degeneracy. Furtherm ore, we have perform ed spin-resolved calculations on the transition m etal complexes to exam ine their electronic structure, as shown in Fig. 4 (further details are available [15]). In neither complex are large degeneracies expected. W hile it is conceivable that the self-assem bled com pounds could have di erent orbital degeneracies than the isolated m olecules, it seems unlikely that both complexes, with their di ering isolated electronic structures, would have such sim ilar properties.

The electronic structure calculations reveal an additional energy scale that is often small in sem iconductor dots, but in the molecular system is comparable energetically to the inferred  $\,$  ,  $E_{\rm c}\,$  , and expected singleparticle level spacing: intram olecular exchange. In both Co and Cu com plexes, intram olecular exchange is strong. In the Co case, to a good approximation ligand eld effects split the d-states into one doubly degenerate, one nearly doubly degenerate, and one singly degenerate set of states. The complex has a total spin of S = 3=2, as con med by EPR. A minority spin half-occupied d state is at the Ferm i level with two nearly degenerate d states 1.1 eV above the Ferm i level and the rem aining occupied minority d electron 0.5 eV below the Fermi level. Exchange splittings pull the majority d-band down signi cantly, with the highest occupied majority d state 1.8 eV below the Ferm i level. The ferm jology is complicated by an additional delocalized unpolarized two-fold degenerate carbon 2p state lying 0.05 eV below the Ferm i level. A lso there is a delocalized doubly degenerate m olecular state 0.85 eV below the Ferm i level. The Cu com plex has a total spin of S = 1=2, with the Ferm i level unchanged in comparison to Co. This means that the minority spin d states are pulled to lower energies by approximately 1.1 eV as shown in the gure. The structure calculations also con m signi cant delocalization of the majority spin states, extending into the ligands, consistent with large values for these systems. Jahn-Teller distortion is not considered, since the substrate-com plex interaction is expected to be large com pared to this e ect.

The occasional observation of K ondo resonances with similar  $T_{\rm K}\,$  values on both sides of charge degeneracy points further indicates that intram olecular exchange cannot be neglected in these devices. How ever, it is not immediately clear how this strong interaction could lead to the observed phenom enon.

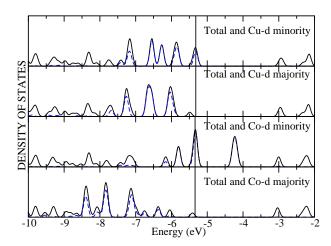


FIG. 4: Spin-resolved projected densities of states of the Cu(II) and Co(II) com plexes, respectively. M inority (upper) and m a prity (lower) spin levels are indicated, demonstrating the strong e ects of intram olecular exchange. The black curve is the total DOS, and the dashed (blue) is the DOS projected onto the transition m etal d states. Further details are available[15].

V ibrational e ects are another piece of physics intrinsic to the molecular system. The signature of electron-phonon interactions has been observed in inelastic electron tunneling spectra of SM T s m ade with these com plexes[14]. M oderate coupling of charge and vibrational m odes[19] localized to the molecule can strongly both increase  $T_K$  and decrease its gate dependence relative to the case with no vibrational coupling [20]. A quantitative estim ate of electron-vibrational couplings would facilitate testing this hypothesis, and should be obtainable from further quantum chem istry calculations.

Finally, it is also possible [21] that screening correla-

In measuring the electronic properties of singlemolecule transistors containing transition metal com – plexes, we observe strong K ondo physics, indicating that conjugated ligands can provide extremely e ective coupling of spin degrees of freedom to metal leads. We also

nd a  $T_k \ (V_G \ )$  that is vastly weaker than that seen in sem iconductor quantum dot realizations of the K ondo e ect and expected for the sim ple m odel of F ig. 1a. We have discussed possible explanations for this anom alous dependence in light of electronic structure calculations of the com plexes. W hile a com plete understanding w ill require m ore sophisticated m odeling and further m easurem ents, these data dem onstrate that correlated states involving SM T s can exhibit rich e ects not seen in their sem iconductor quantum dot counterparts.

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